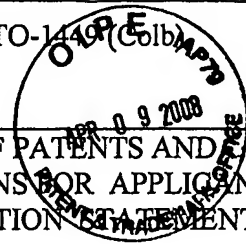


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LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS' INFORMATION	APPLICANT Alex LEVIT, et al.	EXAMINER (N/A)
	FILING DATE March 29, 2004	GROUP ART UNIT 2661

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Examiner's Initials		DOCUMENT NO.	DATE	NAME	CLASS	SUB	FILING DATE
	AA	2001/0032271	10-2001	Allen			
	AB	2003/0147352	08-2003	Ishibashi, et al.			
	AC	2003/0185217	10-2003	Ganti, et al.			
	AD	2004/0109408	06-2004	Mesh, et al.			
	AE	7,197,008	03-2007	Shabtay, et al.			
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	AJ						

OTHER ART (Including Author, Bills, Pertinent Pages, Etc.)

	AK	
	AL	
	AM	
EXAMINER:		DATE CONSIDERED:
<p>EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.</p>		

Notice of References Cited	Application/Control No. 11/305,486	Applicant(s)/Patent Under Reexamination AGMON ET AL.	
	Examiner JEFFREY M. RUTKOWSKI	Art Unit 2619	Page 1 of 1

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*	D	US-2004/0109408 A1	06-2004	Mesh et al.	370/222
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	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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	S					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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